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FAIRCHILD

SEMICONDUCTOR

November 2013

FQB5N90

N-Channel QFET® MOSFET

900 V, 5.4 A, 2.3 Ω

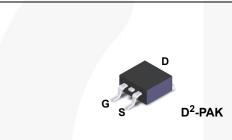
Description

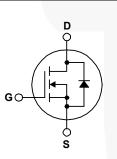
This N-Channel enhancement mode power MOSFET is • 5.4 A, 900 V, $R_{DS(on)}$ = 2.3 Ω (Max.) @ V_{GS} = 10 V, produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state D = 2.7 A Low Gate Charge (Typ. 31 nC) resistance, and to provide superior switching performance . Low Crss (Typ. 13 pF) and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power • 100% Avalanche Tested factor correction (PFC), and electronic lamp ballasts.

Features

- $I_{D} = 2.7 \text{ A}$

- RoHS Compliant





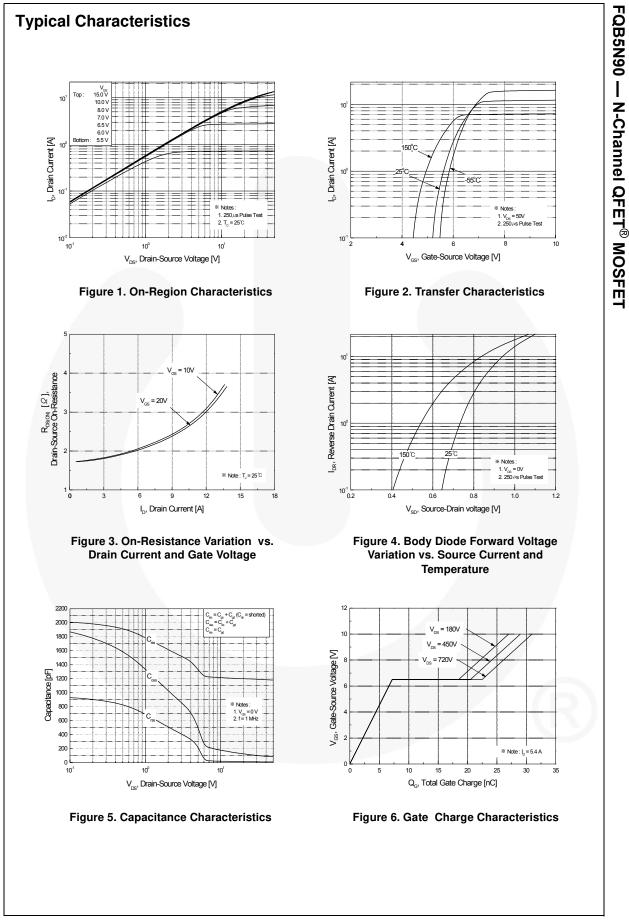
Absolute Maximum Ratings T_c = 25°C unless otherwise noted.

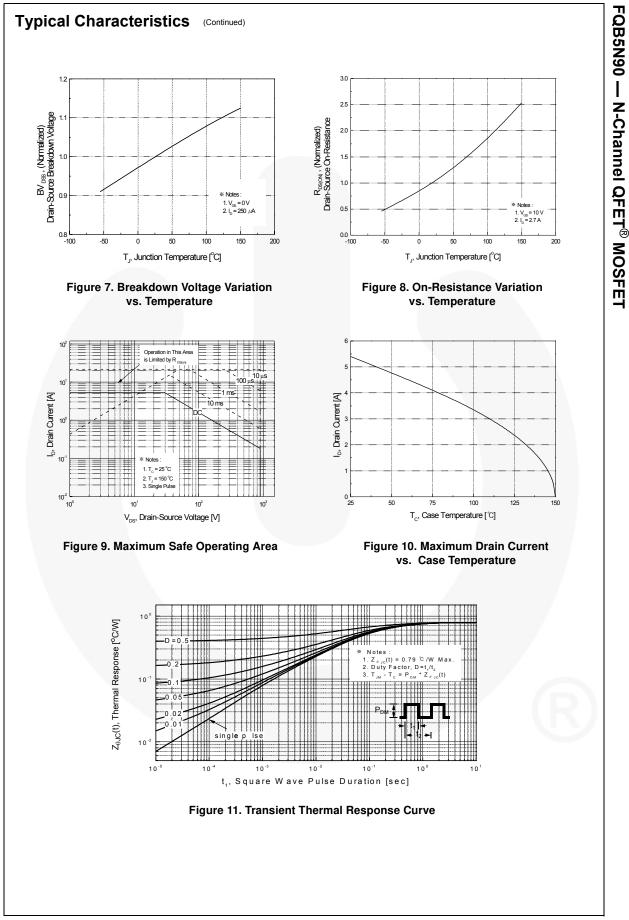
Symbol	Parameter	FC	B5N90TM	Unit
V _{DSS}	Drain-Source Voltage		900	V
I _D	Drain Current - Continuous (T _C = 25°C)		5.4	А
	- Continuous (T _C = 100°C)		3.42	А
I _{DM}	Drain Current - Pulsed (N	ote 1)	21.6	А
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy (N	ote 2)	660	mJ
I _{AR}	Avalanche Current (N	ote 1)	5.4	А
E _{AR}	Repetitive Avalanche Energy (N	ote 1)	15.8	mJ
dv/dt	Peak Diode Recovery dv/dt (N	ote 3)	4.0	V/ns
P _D	Power Dissipation $(T_A = 25^{\circ}C)^{*}$		3.13	W
	Power Dissipation $(T_C = 25^{\circ}C)$		158	W
	- Derate above 25°C		1.27	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range	-{	55 to +150	°C
TL	Maximum lead temperature for soldering, 1/8" from case for 5 seconds		300	°C

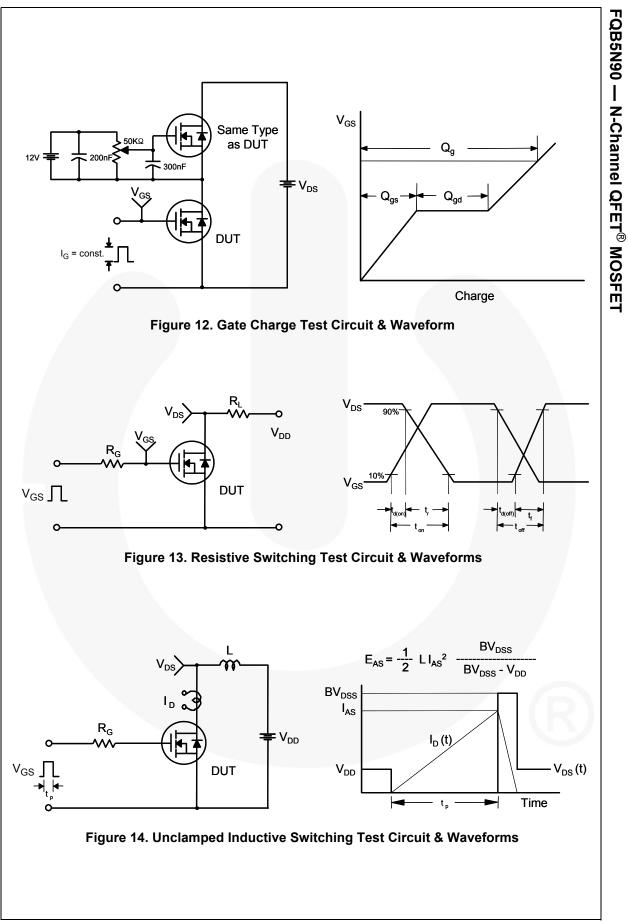
Thermal Characteristics

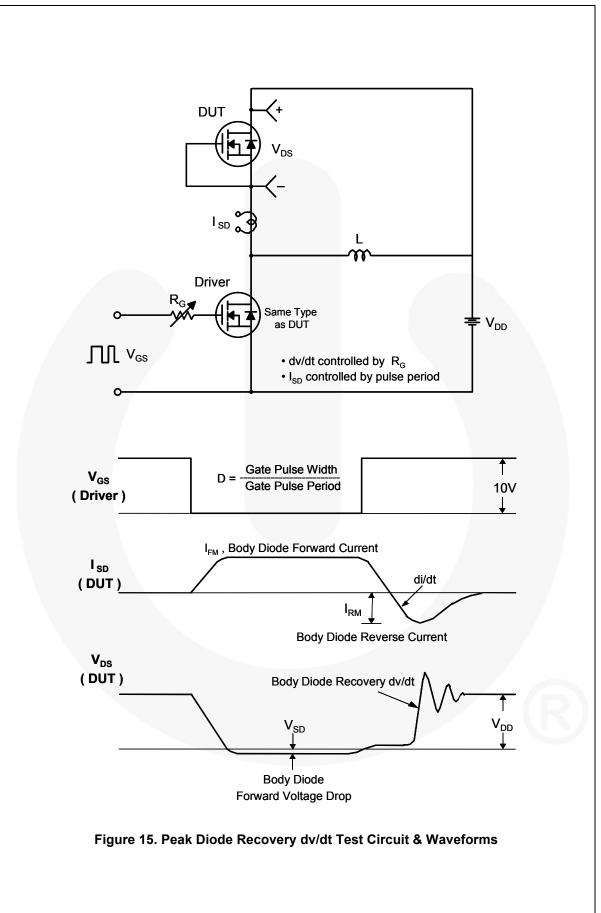
Symbol	Parameter	FQB5N90TM	Unit
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	0.79	
$R_{ hetaJA}$	Thermal Resistance, Junction to Ambient (Minimum Pad of 2-oz Copper), Max.	62.5	°C/W
	Thermal Resistance, Junction to Ambient (*1 in ² Pad of 2-oz Copper), Max.	40	

Part NumberTop MarkPacFQB5N90TMFQB5N90D2-			kage Packing Method Reel			Tape Width		Quantity	
		PAK Tape and Reel 330		mm	24 mm		800 units		
al Cha	racteristics	T _C = 25°0	C unless oth	nerwise noted.					
	Parameter			Test Conditions		Min.	Тур.	Max	. Unit
racterist	ics								
		age	V _{GS} =	0 V, I _D = 250 μA		900			V
		•							
	U 1		$I_D = 250 \mu$ A, Referenced to 25°C			1.0		V/°C	
Zoro Coto	Valtaga Drain Curr	ont						10	μA
Zero Gate Voltage Drain Current		V _{DS} = 720 V, T _C = 125°C				100	μA		
Gate-Bod	ody Leakage Current, Forward		V_{GS} = 30 V, V_{DS} = 0 V					100	nA
Gate-Bod	y Leakage Current,	Reverse	V _{GS} =	-30 V, V _{DS} = 0 V				-100	nA
		_	V			0.0		F 0	
	Ū,	_	V _{DS} =	v_{GS} , $I_D = 250 \mu\text{A}$		3.0		5.0	V
			V _{GS} =7	V_{GS} = 10 V, I _D = 2.7 A			1.8	2.3	Ω
Forward T	orward Transconductance		V _{DS} = 50 V, I _D = 2.7 A				5.6		S
Chara	steristics								
		-	V -				1200	1550	pF
		_							pF
		2	1 – 1.0				-		pF
		-							- F -
ng Chara	acteristics								
Turn-On [Delay Time						00	6 E	20
			Vpp =	$450 \text{ V} \text{ I}_{\text{D}} = 5.4 \text{ A}$			28	65	ns
Turn-On F	,	-		450 V, I _D = 5.4 A, 5 Ω			28 65	140	ns
Turn-On F	,	_	V _{DD} = R _G = 2	—					
Turn-On F	Rise Time Delay Time			—	(Note 4)		65	140	ns
Turn-On F Turn-Off E	Rise Time Delay Time Fall Time		R _G = 2	—	(Note 4)		65 65	140 140	ns
Turn-On F Turn-Off D Turn-Off F Total Gate	Rise Time Delay Time Fall Time		R _G = 2	720 V, I _D = 5.4 A,	(Note 4)	 	65 65 50	140 140 110	ns ns ns
Turn-On F Turn-Off D Turn-Off F Total Gate	Rise Time Delay Time Call Time Charge rce Charge		R _G = 2 V _{DS} =	720 V, I _D = 5.4 A,	(Note 4) (Note 4)	 	65 65 50 31	140 140 110 40	ns ns ns nC
Turn-On F Turn-Off E Turn-Off F Total Gate Gate-Sour Gate-Drai	Rise Time Delay Time all Time e Charge rce Charge n Charge	stics a	R _G = 2 V _{DS} = V _{GS} =	720 V, I _D = 5.4 A, 10 V		 	65 65 50 31 7.2	140 140 110 40 	ns ns ns nC nC
Turn-On F Turn-Off E Turn-Off F Total Gate Gate-Sou Gate-Drai	Rise Time Delay Time Fall Time Charge rce Charge n Charge ode Characteri		$R_G = 2$ $V_{DS} =$ $V_{GS} =$	720 V, I _D = 5.4 A, 10 V kimum Ratings		 	65 65 50 31 7.2	140 140 110 40 	ns ns nC nC nC
Turn-On F Turn-Off E Turn-Off F Total Gate Gate-Sou Gate-Drai Durce Di Maximum	Rise Time Delay Time Fall Time Charge rce Charge n Charge ode Characteri Continuous Drain-S	Source Did	$R_{G} = 2$ $V_{DS} =$ $V_{GS} =$ $N_{GS} =$	T20 V, $I_D = 5.4$ A, 10 V timum Ratings rard Current		 	65 65 50 31 7.2 15	140 140 110 40 5.4	ns ns nC nC nC A
Turn-On F Turn-Off E Turn-Off F Total Gate Gate-Sour Gate-Drai Durce Di Maximum Maximum	Rise Time Delay Time Fall Time Charge rce Charge n Charge ode Characteri Continuous Drain-S Pulsed Drain-Source	Source Dic e Diode F	$R_{G} = 2$ $V_{DS} =$ $V_{GS} =$ $V_{GS} =$ $N_{CS} =$	T20 V, $I_D = 5.4$ A, 10 V kimum Ratings rard Current Current		 	65 65 50 31 7.2 15	140 140 110 40 5.4 21.6	ns ns nC nC nC A
Turn-On F Turn-Off E Turn-Off F Total Gate Gate-Sou Gate-Drai Durce Di Maximum Maximum Drain-Sou	Rise Time Delay Time Fall Time Charge rce Charge n Charge ode Characteri Continuous Drain-S	Source Dic e Diode F	$R_{G} = 2$ $V_{DS} =$ $V_{GS} =$ $M M M M M M M M M M M M M M M M M M M $	T20 V, $I_D = 5.4$ A, 10 V timum Ratings rard Current		 	65 65 50 31 7.2 15	140 140 110 40 5.4	ns ns nC nC nC nC
	Drain-Sou Breakdow Coefficien Zero Gate Gate-Bod Gate-Bod Gate-Bod Gate-Bod Gate Three Static Dra On-Resist Forward T C Charac Input Cap Output Ca Reverse T	racteristics Drain-Source Breakdown Volt Breakdown Voltage Temperat Coefficient Zero Gate Voltage Drain Current, Gate-Body Leakage Current, Gate-Body Leakag	racteristics Drain-Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate-Body Leakage Current, Forward Gate-Body Leakage Current, Reverse racteristics Gate Threshold Voltage Static Drain-Source On-Resistance Forward Transconductance c Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance	racteristicsDrain-Source Breakdown Voltage V_{GS} =Breakdown Voltage Temperature Coefficient I_D = 25Zero Gate Voltage Drain Current V_{DS} =Gate-Body Leakage Current, Forward V_{GS} =Gate-Body Leakage Current, Reverse V_{GS} =Gate Threshold Voltage V_{DS} =Static Drain-Source On-Resistance V_{DS} =Forward 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MHz}$	racteristicsDrain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}, I_D = 250 \mu \text{A}$ Breakdown Voltage Temperature Coefficient $I_D = 250 \mu \text{A}, \text{Referenced to } 25^{\circ}\text{C}$ Zero Gate Voltage Drain Current $V_{DS} = 900 \text{ V}, V_{GS} = 0 \text{ V}$ Zero Gate Voltage Drain Current $V_{DS} = 720 \text{ V}, T_C = 125^{\circ}\text{C}$ Gate-Body Leakage Current, Forward $V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$ Gate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \mu \text{A}$ Static Drain-Source On-Resistance $V_{GS} = 10 \text{ V}, I_D = 2.7 \text{ A}$ Forward Transconductance $V_{DS} = 50 \text{ V}, I_D = 2.7 \text{ A}$ CharacteristicsInput CapacitanceInput Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$	racteristicsDrain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}, I_D = 250 \mu \text{A}$ 900Breakdown Voltage Temperature Coefficient 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\text{Referenced to } 25^{\circ}\text{C}$ 1.0 Zero Gate Voltage Drain Current $V_{DS} = 900 \text{ V}, V_{GS} = 0 \text{ V}$ Gate-Body Leakage Current, Forward $V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$ Gate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \mu \text{A}$ 3.0 Static Drain-Source On-Resistance $V_{DS} = 50 \text{ V}, I_D = 2.7 \text{ A}$ 1.8 Forward Transconductance $V_{DS} = 50 \text{ V}, I_D = 2.7 \text{ A}$ 5.6 CharacteristicsInput Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = 2.7 \text{ A}$ 1200 Output Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = 2.7 \text{ A}$ 1.3	racteristics Drain-Source Breakdown Voltage $V_{GS} = 0 V$, $I_D = 250 \mu A$ 900 Breakdown Voltage Temperature Coefficient $I_D = 250 \mu A$, Referenced to $25^{\circ}C$ 1.0 Zero Gate Voltage Drain Current $V_{DS} = 900 V$, $V_{GS} = 0 V$ 100 Gate-Body Leakage Current, Forward $V_{GS} = 30 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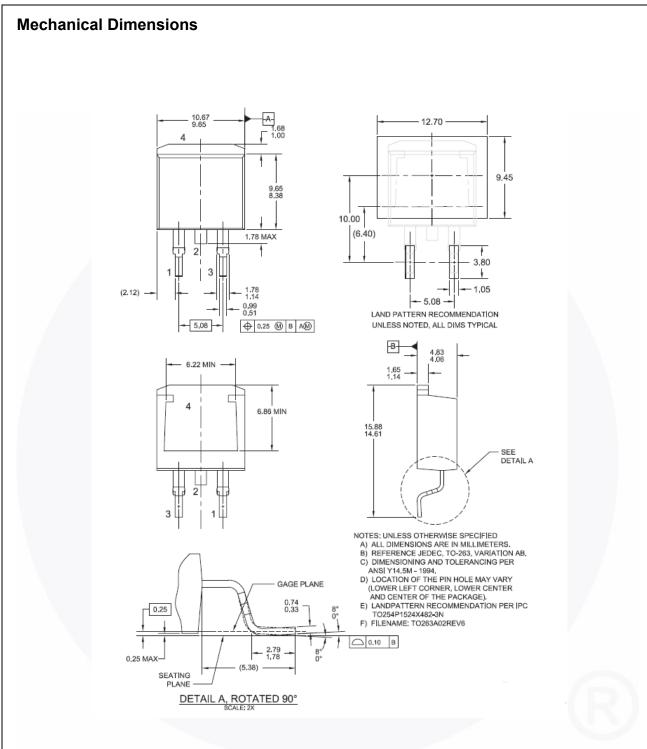


Figure 16. TO263 (D²PAK), Molded, 2-Lead, Surface Mount

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N-Channel QFET[®] MOSFET

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